

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination FUNAKOSHI ET AL.	
		Examiner John M. Villecco	Art Unit 2612	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,587,144	07-2003	Kim, Min-Gyu	348/241
	B	US-6,580,465	06-2003	Sato, Koichi	348/689
	C	US-6,597,395	07-2003	Kim et al.	348/222.1
	D	US-6,606,118	08-2003	Watanabe, Takashi	348/243
	E	US-5,995,166	11-1999	Kawano, Tsutomu	348/689
	F	US-6,791,607	09-2004	Bilhan et al.	348/243
	G	US-4,816,917	03-1989	Yamamoto et al.	348/257
	H	US-4,553,169	11-1985	Yoshioka et al.	348/243
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 04291576 A	10-1992	Japan	SUZUKI et al.	H04N 05/18
	O	JP 04291590 A	10-1992	Japan	OKADA et al.	H04N 07/18
	P	JP 08102893 A	04-1996	Japan	KATO, SATOSHI	H04N 05/335
	Q	JP 07184128 A	07-1995	Japan	ISHIBASHI, OSAMU	H04N 05/335
	R	DE 2003455 B	04-1977	Germany		H04N 05/18
	S	JP 02009275 A	01-1990	Japan	HASHIGUCHI, TOKUICHI	H04N 05/18
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.